



# 512K x 8 Static RAM Module

## Features

- High-density 4-megabit SRAM module
- High-speed CMOS SRAMs
  - Access time of 35 ns
- Low active power
  - 3.4W (max.)
- Double-sided SMD technology
- TTL-compatible inputs and outputs
- Low profile version (PF)
  - Max. height of .345 in.
- Small footprint SIP version (PS)
  - PCB layout area of 1.2 sq. in.

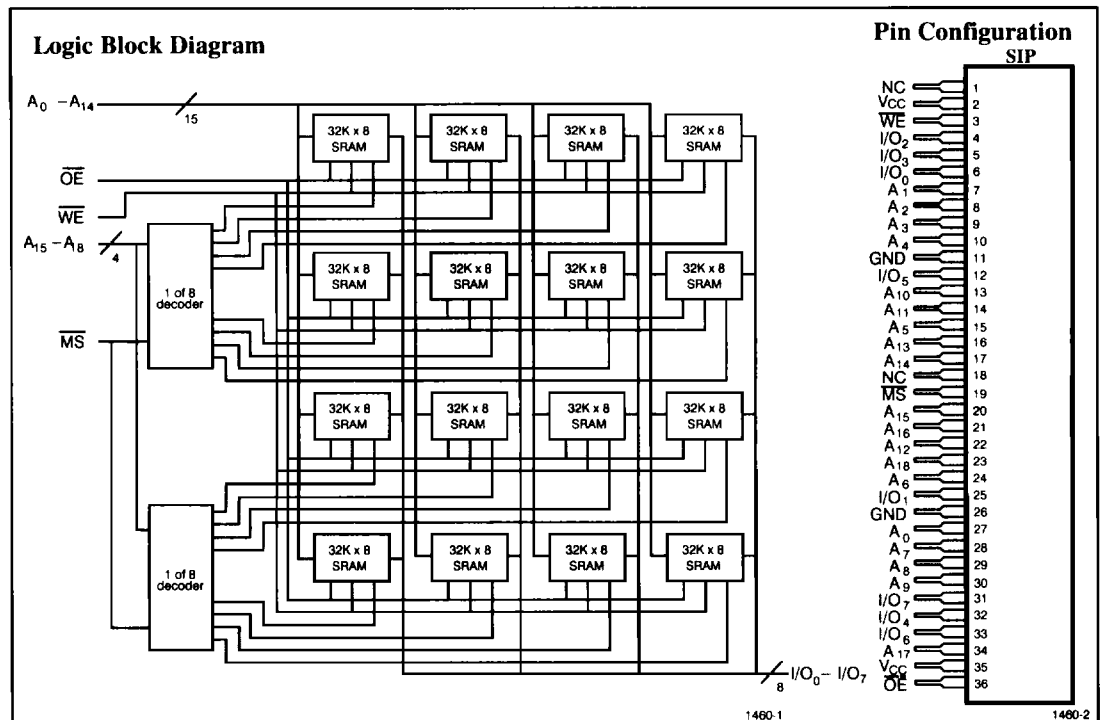
## Functional Description

The CYM1460 is a high-performance 4-megabit static RAM module organized as 512K words by 8 bits. This module is constructed from sixteen 32K x 8 SRAMs in plastic surface mount packages on an epoxy laminate board with pins. Two choices of pins are available for vertical (PS) or horizontal (PF) through-hole mounting. On-board decoding selects one of the sixteen SRAMs from the high-order address lines, keeping the remaining fifteen devices in standby mode for minimum power consumption.

An active LOW write enable signal ( $\overline{WE}$ ) controls the writing/reading operation of

the memory. When  $\overline{MS}$  and  $\overline{WE}$  inputs are both LOW, data on the eight data input/output pins is written into the memory location specified on the address pins. Reading the device is accomplished by selecting the device and enabling the outputs,  $\overline{MS}$  and  $\overline{OE}$ , active LOW, while  $\overline{WE}$  remains inactive or HIGH. Under these conditions, the content of the location addressed by the information on the address pins is present on the eight data input/output pins.

The input/output pins remain in a high-impedance state unless the module is selected, outputs are enabled, and write enable ( $\overline{WE}$ ) is HIGH.



## Selection Guide

	1460-35	1460-45	1460-55	1460-70
Maximum Access Time (ns)	35	45	55	70
Maximum Operating Current (mA)	625	625	625	625
Maximum Standby Current (mA)	560	560	560	560

### Maximum Ratings

(Above which the useful life may be impaired)

Storage Temperature .....	-65°C to +150°C
Ambient Temperature with Power Applied .....	0°C to +70°C
Supply Voltage to Ground Potential .....	-0.5V to +7.0V
DC Voltage Applied to Outputs in High Z State .....	-0.5V to +7.0V
DC Input Voltage .....	-0.5V to +7.0V

### Operating Range

Range	Ambient Temperature	V <sub>CC</sub>
Commercial	0°C to +70°C	5V ± 10%

### Electrical Characteristics Over the Operating Range

Parameters	Description	Test Conditions	CYM1460		Units
			Min.	Max.	
V <sub>OH</sub>	Output HIGH Voltage	V <sub>CC</sub> = Min., I <sub>OH</sub> = -4.0 mA	2.4		V
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> = Min., I <sub>OL</sub> = 8.0 mA	0.4	V	
V <sub>IH</sub>	Input HIGH Voltage		2.2	V <sub>CC</sub>	V
V <sub>IL</sub>	Input LOW Voltage		-0.5	0.8	V
I <sub>IX</sub>	Input Load Current	GND ≤ V <sub>I</sub> ≤ V <sub>CC</sub>	-20	+20	μA
I <sub>OZ</sub>	Output Leakage Current	GND ≤ V <sub>I</sub> ≤ V <sub>CC</sub> Output Disabled	-20	+20	μA
I <sub>CC</sub>	V <sub>CC</sub> Operating Supply Current	V <sub>CC</sub> = Max., MS < V <sub>IL</sub> I <sub>OUT</sub> = 0 mA		625	mA
I <sub>SB1</sub>	Automatic $\overline{MS}$ Power-Down Current	Max. V <sub>CC</sub> , $\overline{MS} \geq V_{IH}$ Min. Duty Cycle = 100%		560	mA
I <sub>SB2</sub>	Automatic $\overline{MS}$ Power-Down Current	Max. V <sub>CC</sub> , $\overline{MS} \geq V_{CC} - 0.2V$ , V <sub>IN</sub> ≥ V <sub>CC</sub> - 0.2V or V <sub>IN</sub> ≤ 0.2V		320	mA

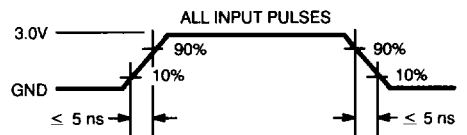
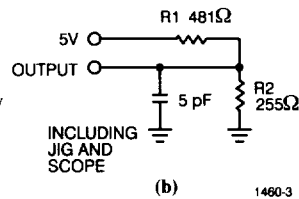
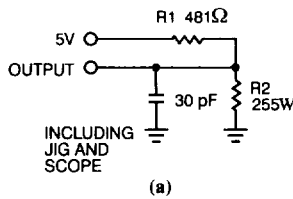
### Capacitance<sup>[1]</sup>

Parameters	Description	Test Conditions	Max.	Unit
C <sub>IN</sub>	Input Capacitance	T <sub>A</sub> = 25°C, f = 1 MHz V <sub>CC</sub> = 5.0V	120	pF
C <sub>OUT</sub>	Output Capacitance		180	pF

**Notes:**

1. Tested on a sample basis.

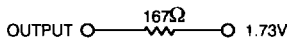
### AC Test Loads and Waveforms



1460-3

1460-4

Equivalent to: THEVENIN EQUIVALENT



### Switching Characteristics Over the Operating Range <sup>[2]</sup>

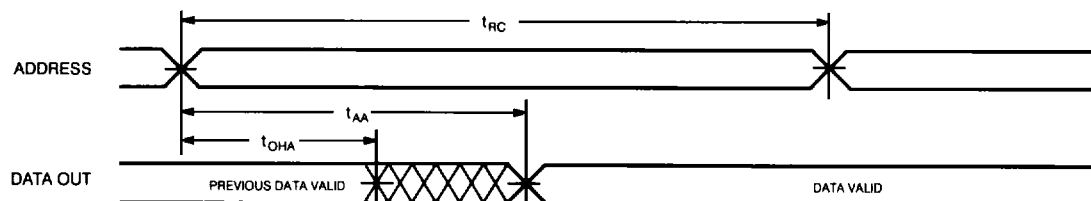
Parameters	Description	1460-35		1460-45		1460-55		1460-70		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
<b>READ CYCLE</b>										
t <sub>RC</sub>	Read Cycle Time	35		45		55		70		ns
t <sub>AA</sub>	Address to Data Valid		35		45		55		70	ns
t <sub>OHA</sub>	Data Hold from Address Change	3		3		3		3		ns
t <sub>AMS</sub>	$\overline{MS}$ LOW to Data Valid		35		45		55		70	ns
t <sub>DOE</sub>	$\overline{OE}$ LOW to Data Valid		15		20		25		30	ns
t <sub>LZOE</sub>	$\overline{OE}$ LOW to Low Z	0		0		0		0		ns
t <sub>HZOE</sub>	$\overline{OE}$ HIGH to High Z <sup>[3]</sup>		15		25		25		30	ns
t <sub>LZMS</sub>	$\overline{MS}$ LOW to Low Z <sup>[4]</sup>	5		5		5		5		ns
t <sub>HZMS</sub>	$\overline{MS}$ HIGH to High Z <sup>[3,4]</sup>		15		20		25		35	ns
<b>WRITE CYCLE</b> <sup>[5]</sup>										
t <sub>WC</sub>	Write Cycle Time	35		45		55		70		ns
t <sub>SMS</sub>	$\overline{MS}$ LOW to Write End	30		40		50		60		ns
t <sub>AW</sub>	Address Set-Up to Write End	30		40		50		60		ns
t <sub>HA</sub>	Address Hold from Write End	5		5		5		5		ns
t <sub>SA</sub>	Address Set-Up to Write Start	5		5		5		5		ns
t <sub>PWE</sub>	$\overline{WE}$ Pulse Width	25		30		40		55		ns
t <sub>SD</sub>	Data Set-Up to Write End	15		20		25		30		ns
t <sub>HD</sub>	Data Hold from Write End	5		5		5		5		ns
t <sub>HZWE</sub>	$\overline{WE}$ LOW to High Z <sup>[3]</sup>		15		20		25		25	ns
t <sub>LZWE</sub>	$\overline{WE}$ HIGH to Low Z	3		3		3		3		ns

**Notes:**

- Test conditions assume signal transition times of 5 ns or less, timing reference levels of 1.5V, input levels of 0 to 3.0V and output loading of the specified I<sub>O1</sub>/I<sub>OH</sub> and 30-pF load capacitance.
- t<sub>HZOE</sub>, t<sub>HZMS</sub> and t<sub>HZWE</sub> are specified with C<sub>L</sub> = 5 pF as in part (b) of AC Test Loads. Transition is measured ±500 mV from steady state voltage.
- At any given temperature and voltage condition, t<sub>HZMS</sub> is less than t<sub>LZMS</sub> for any given device. These parameters are guaranteed and not 100% tested.
- The internal write time of the memory is defined by the overlap of  $\overline{MS}$  LOW and  $\overline{WE}$  LOW. Both signals must be LOW to initiate a write and either signal can terminate a write by going HIGH. The data input set-up and hold timing should be referenced to the rising edge of the signal that terminates the write.
- $\overline{WE}$  is HIGH for read cycle.
- Device is continuously selected.  $\overline{OE}$ ,  $\overline{MS}$  = V<sub>II</sub>.
- Address valid prior to or coincident with  $\overline{MS}$  transition LOW.
- Data I/O is HIGH impedance if  $\overline{OE}$  = V<sub>IH</sub>.
- If  $\overline{MS}$  goes HIGH simultaneously with  $\overline{WE}$  HIGH, the output remains in a high-impedance state.

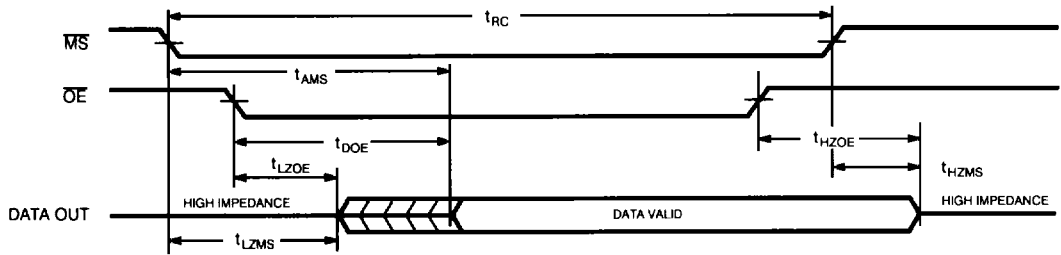
### Switching Waveforms

Read Cycle No. 1 <sup>[6,7]</sup>



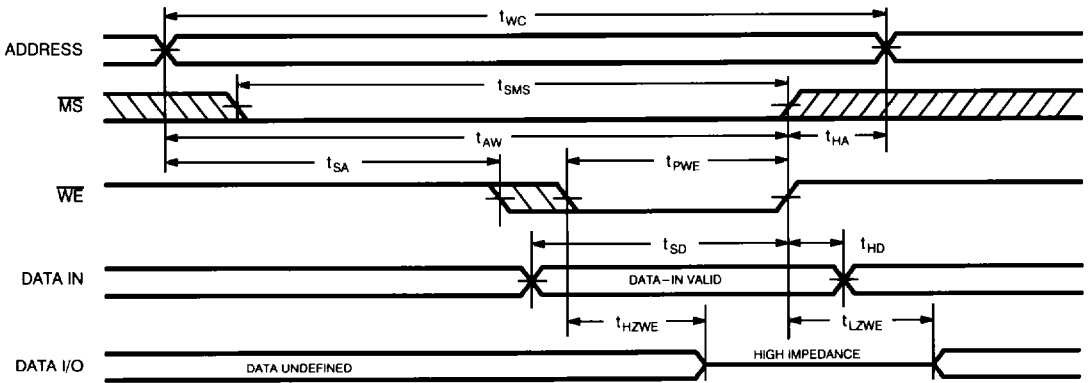
**Switching Waveforms** (continued)

**Read Cycle No. 2** [6, 8]



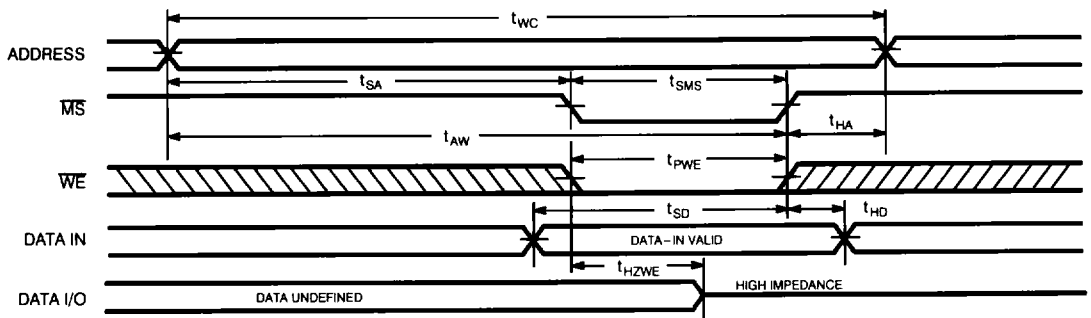
1460-6

**Write Cycle No. 1 (WE Controlled)** [5, 9]



1460-7

**Write Cycle No. 2 (MS Controlled)** [5, 9, 10]



1460-8

9  
MODULES

**Truth Table**

$\overline{MS}$	$\overline{WE}$	$\overline{OE}$	Input/Outputs	Mode
H	X	X	High Z	Deselect/Power-Down
L	H	L	Data Out	Read
L	L	X	Data In	Write
L	H	H	High Z	Deselect

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**Ordering Information**

Speed	Ordering Code	Package Type	Operating Range
35	CYM1460PS-35C	PS05	Commercial
	CYM1460PF-35C	PF03	
45	CYM1460PS-45C	PS05	Commercial
	CYM1460PF-45C	PF03	
55	CYM1460PS-55C	PS05	Commercial
	CYM1460PF-55C	PF03	
70	CYM1460PS-70C	PS05	Commercial
	CYM1460PF-70C	PF03	